



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of “Quality Parts,Customers Priority,Honest Operation,and Considerate Service”,our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China





12-Bit Monitor and Control System with Multichannel ADC, DACs, Temperature Sensor, and Current Sense

Data Sheet

AD7294

FEATURES

- 12-bit SAR ADC with 3 μ s conversion time**
 - 4 uncommitted analog inputs**
 - Differential/single-ended
 - V_{REF} , $2 \times V_{REF}$ input ranges
 - 2 high-side current sense inputs**
 - 5 V to 59.4 V operating range
 - 0.5% max gain error
 - ± 200 mV input range
 - 2 external diode temperature sensor inputs**
 - -55°C to $+150^{\circ}\text{C}$ measurement range
 - $\pm 2^{\circ}\text{C}$ accuracy
 - Series resistance cancellation
 - 1 internal temperature sensor**
 - $\pm 2^{\circ}\text{C}$ accuracy
 - Built-in monitoring features**
 - Minimum/maximum recorder for each channel
 - Programmable alert thresholds
 - Programmable hysteresis
 - Four 12-bit monotonic 15 V DACs**
 - 5 V span, 0 V to 10 V offset
 - 8 μ s settling time
 - 10 mA sink and source capability
 - Power-on resets (POR) to 0 V
 - Internal 2.5 V reference**
 - 2-wire fast mode I²C interface**
 - Temperature range: -40°C to $+105^{\circ}\text{C}$**
 - Package type: 64-lead TQFP or 56-lead LFCSP**

APPLICATIONS

- Cellular base stations**
 - GSM, EDGE, UMTS, CDMA, TD-SCDMA, W-CDMA, WiMAX
- Point-to-multipoint and other RF transmission systems**
- 12 V, 24 V, 48 V automotive applications**
- Industrial controls**

GENERAL DESCRIPTION

The AD7294 contains all the functions required for general-purpose monitoring and control of current, voltage, and temperature integrated into a single-chip solution. The device includes low voltage (± 200 mV) analog input sense amplifiers for current monitoring across shunt resistors, temperature sense inputs, and four uncommitted analog input channels multiplexed into a SAR analog-to-digital converter (ADC) with a 3 μ s conversion time. A high accuracy internal reference is provided to drive both the digital-to-analog converter (DAC) and ADC. Four 12-bit DACs provide the outputs for voltage control. The AD7294 also includes limit registers for alarm functions. The device is designed on Analog Devices, Inc., high voltage DMOS process for high voltage compliance, 59.4 V on the current sense inputs, and up to a 15 V DAC output voltage.

The AD7294 is a highly integrated solution that offers all the functionality necessary for precise control of the power amplifier in cellular base station applications. In these types of applications, the DACs provide 12-bit resolution to control the bias currents of the power transistors. Thermal diode-based temperature sensors are incorporated to compensate for temperature effects. The ADC monitors the high-side current and temperature. All this functionality is provided in a 64-lead TQFP or a 56-lead LFCSP operating over a temperature range of -40°C to $+105^{\circ}\text{C}$.

Rev. I

[Document Feedback](#)

Information furnished by Analog Devices is believed to be accurate and reliable. However, no responsibility is assumed by Analog Devices for its use, nor for any infringements of patents or other rights of third parties that may result from its use. Specifications subject to change without notice. No license is granted by implication or otherwise under any patent or patent rights of Analog Devices. Trademarks and registered trademarks are the property of their respective owners.

One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A.
Tel: 781.329.4700 ©2008–2016 Analog Devices, Inc. All rights reserved.
[Technical Support](#) www.analog.com

AD7294* PRODUCT PAGE QUICK LINKS

Last Content Update: 02/23/2017

COMPARABLE PARTS

View a parametric search of comparable parts.

EVALUATION KITS

- AD7294 Evaluation Board

DOCUMENTATION

Data Sheet

- AD7294: 12-Bit Monitor and Control System with Multichannel ADC, DACs, Temperature Sensor, and Current Sense Data Sheet

User Guides

- UG-1004: Evaluating the AD7294 12-Bit Monitor and Control System with Multichannel ADC, DACs, Temperature Sensor, and Current Sense

REFERENCE MATERIALS

Technical Articles

- MS-2210: Designing Power Supplies for High Speed ADC

DESIGN RESOURCES

- AD7294 Material Declaration
- PCN-PDN Information
- Quality And Reliability
- Symbols and Footprints

DISCUSSIONS

View all AD7294 EngineerZone Discussions.

SAMPLE AND BUY

Visit the product page to see pricing options.

TECHNICAL SUPPORT

Submit a technical question or find your regional support number.

DOCUMENT FEEDBACK

Submit feedback for this data sheet.

TABLE OF CONTENTS

Features	1	TSENSE1, TSENSE2 Result Registers (0x02 and 0x03)	29
Applications	1	TSENSEINT Result Register (0x04)	29
General Description	1	DAC _A , DAC _B , DAC _C , DAC _D , Registers (0x01 to 0x04)	30
Revision History	3	Alert Status Register A (0x05), Register B (0x06), and Register C (0x07)	30
Functional Block Diagram	4	Channel Sequence Register (0x08)	30
Specifications	5	Configuration Register (0x09)	31
DAC Specifications	5	Power-Down Register (0x0A)	32
ADC Specifications	6	DATA _{HIGH} /DATA _{LOW} Registers: 0x0B, 0x0C (V _{IN0}); 0x0E, 0x0F (V _{IN1}); 0x11, 0x12 (V _{IN2}); 0x14, 0x15 (V _{IN3})	32
General Specifications	8	Hysteresis Registers: 0x0D (VIN0), 0x10 (VIN1), 0x13 (VIN2), 0x16 (VIN3)	32
Timing Characteristics	9	T _{SENSE} Offset Registers (0x26 and 0x27)	33
Absolute Maximum Ratings	10	I ² C Interface	34
Thermal Resistance	10	General I ² C Timing	34
ESD Caution	10	Serial Bus Address Byte	35
Pin Configurations and Function Descriptions	11	Interface Protocol	35
Typical Performance Characteristics	14	Modes of Operation	39
Terminology	19	Command Mode	39
DAC Terminology	19	Autocycle Mode	40
ADC Terminology	19	Alerts and Limits Theory	41
Theory of Operation	20	Alert_Flag Bit	41
ADC Overview	20	Alert Status Registers	41
ADC Transfer Functions	20	Data _{HIGH} and Data _{LOW} Monitoring Features	41
Analog Inputs	20	Hysteresis	42
Current Sensor	22	Applications Information	43
Analog Comparator Loop	23	Base Station Power Amplifier Monitor and Control	43
Temperature Sensor	24	Gain Control of Power Amplifier	44
DAC Operation	25	Layout and Configuration	45
ADC and DAC Reference	25	Power Supply Bypassing and Grounding	45
V _{DRIVE} Feature	26	Outline Dimensions	46
Register Setting	27	Ordering Guide	46
Address Pointer Register	27		
Command Register (0x00)	28		
Result Register (0x01)	28		

REVISION HISTORY**2/16—Rev. H to Rev. I**

Changed CP-56-1 to CP-56-11	Throughout
Changes to Figure 4	11
Updated Outline Dimensions	46
Changes to Ordering Guide	46

1/12—Rev. G to Rev. H

Changes to Table 2	6
--------------------------	---

11/11—Rev. F to Rev. G

Change to DAC Output Characteristics Parameter of Table 1	5
Deleted DAC HIGH-Z Pin Leakage from Table 3	8
Change to Figure 4	11
Changes to Table 7	12
Deleted Figure 47; Renumbered Sequentially	25
Deleted High Impedance Input Pin Section	26

11/10—Rev. E to Rev. F

Change to Table 2, Dynamic Performance, Spurious-Free Dynamic Range (SFDR)	6
---	---

10/10—Rev. D to Rev. E

Change to Reflow Temperature, Table 5	10
---	----

5/10—Rev. C to Rev. D

Added 56-Lead LFCSP	Universal
Change to Features Section and General Description Section ...	1

Changes to Table 2	6
Changes to Table 6	10
Added Figure 4	11
Changes to Table 7	12
Changes to Command Register Section	28
Changes to Autocycle Mode Section	40
Updated Outline Dimensions	47
Changes to Ordering Guide	48

7/09—Rev. B to Rev. C

Changes to Table 4 Endnotes	8
-----------------------------------	---

4/09—Rev. A to Rev. B

Changes to Table 2	6
Changes to Table 3	7
Changes to Table 23	29

3/09—Rev. 0 to Rev. A

Changes to Configuration Register (0x09) Section	29
Changes to Table 23 and Table 24	29
Changes to Table 27	30
Changes to Autocycle Mode Section	38
Change to Alert Status Registers Section	39
Changes to DATA _{HIGH} and DATA _{LOW} Monitoring Features Section	39

1/08—Revision 0: Initial Version

FUNCTIONAL BLOCK DIAGRAM

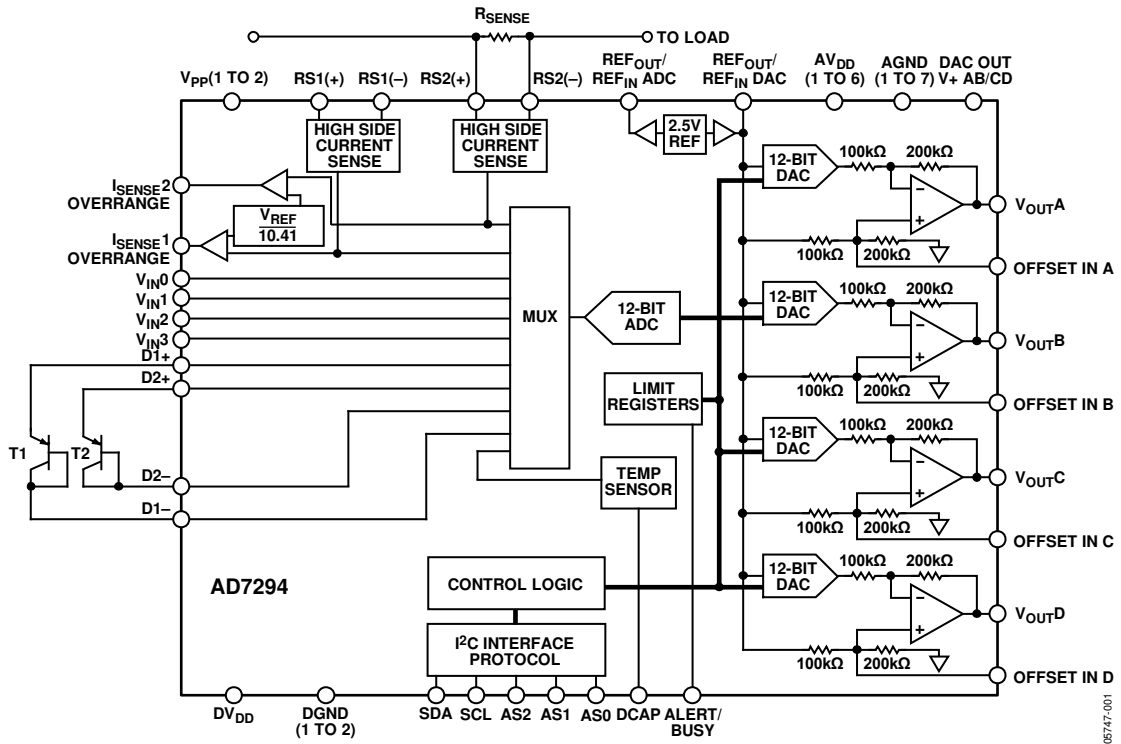


Figure 1.

65747-001

SPECIFICATIONS

DAC SPECIFICATIONS

$AV_{DD} = DV_{DD} = 4.5 \text{ V to } 5.5 \text{ V}$, $AGND = DGND = 0 \text{ V}$, internal 2.5 V reference; $V_{DRIVE} = 2.7 \text{ V to } 5.5 \text{ V}$; $T_A = -40^\circ\text{C to } +105^\circ\text{C}$, unless otherwise noted. DAC OUTV+ AB and DAC OUTV+ CD = 4.5 V to 16.5 V, OFFSET IN x is floating, therefore, the DAC output span = 0 V to 5 V.

Table 1.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
ACCURACY					
Resolution	12			Bits	
Relative Accuracy (INL)		±1	±3	LSB	
Differential Nonlinearity (DNL)		±0.3	±1	LSB	Guaranteed monotonic
Zero-Scale Error		2.5	8	mV	
Full-Scale Error of DAC and Output Amplifier			15.5 ¹	mV	DAC OUTV+ = 5.0 V
Full-Scale Error of DAC		2		mV	DAC OUTV+ = 15.0 V
Offset Error			±8.575	mV	Measured in the linear region, $T_A = -40^\circ\text{C to } +105^\circ\text{C}$
			±2	mV	Measured in the linear region, $T_A = 25^\circ\text{C}$
Offset Error Temperature Coefficient		±5		ppm/°C	
Gain Error		±0.025	±0.155	% FSR	
Gain Temperature Coefficient		±5		ppm/°C	
DAC OUTPUT CHARACTERISTICS					
Output Voltage Span	0		$2 \times V_{REF}$	V	0 V to 5 V for a 2.5 V reference
Output Voltage Offset	0		10	V	The output voltage span can be positioned in the 0 V to 15 V range; if the OFFSET IN x is left floating, the offset pin = $2/3 \times V_{REF}$, giving an output of 0 V to $2 \times V_{REF}$
Offset Input Pin Range	0		5		$V_{OUT} = 3 V_{OFFSET} - 2 \times V_{REF} + V_{DAC}$
DC Input Impedance ²		75		kΩ	100 kΩ to V_{REF} , and 200 kΩ to AGND, see Figure 48
Output Voltage Settling Time ²		8		μs	1/4 to 3/4 change within 1/2 LSB, measured from last SCL edge
Slew Rate ²		1.1		V/μs	
Short-Circuit Current ²		40		mA	Full-scale current shorted to ground
Load Current ²		±10		mA	Source and/or sink within 200 mV of supply
Capacitive Load Stability ²	10			nF	$R_L = \infty$
DC Output Impedance ²		1		Ω	
REFERENCE					
Reference Output Voltage	2.49	2.5	2.51	V	±0.4% maximum at 25°C, $AV_{DD} = DV_{DD} = 4.5 \text{ V to } 5.5 \text{ V}$
Reference Input Voltage Range	0		$AV_{DD} - 2$	V	
Input Current		100	125	μA	$V_{REF} = 2.5 \text{ V}$
Input Capacitance ²		20		pF	
V_{REF} Output Impedance ²		25		Ω	
Reference Temperature Coefficient		10	25	ppm/°C	

¹ This value indicates that the DAC output amplifiers can output voltages 15.5 mV below the DAC OUTV+ supply. If higher DAC OUTV+ supply voltages are used, the full-scale error of the DAC is typically 2 mV with no load.

² Samples are tested during initial release to ensure compliance; they are not subject to production testing.

ADC SPECIFICATIONS

$AV_{DD} = DV_{DD} = 4.5\text{ V to }5.5\text{ V}$, $AGND = DGND = 0\text{ V}$, $V_{REF} = 2.5\text{ V}$ internal or external; $V_{DRIVE} = 2.7\text{ V to }5.5\text{ V}$; $V_{PP} = AV_{DD}$ to 59.4 V ; $T_A = -40^\circ\text{C to }+105^\circ\text{C}$, unless otherwise noted.

Table 2.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
DC ACCURACY					
Resolution		12		Bits	
Integral Nonlinearity (INL) ¹		±0.5	±1	LSB	Differential mode
		±0.5	±1.5	LSB	Single-ended or pseudo differential mode
Differential Nonlinearity (DNL) ¹		±0.5	±0.99	LSB	Differential, single-ended, and pseudo differential modes
Single-Ended Mode					
Offset Error		±1	±7	LSB	
Offset Error Match		±0.4		LSB	
Gain Error		±0.5	±2.5	LSB	
Gain Error Match		±0.4		LSB	
Differential Mode					
Positive Gain Error		±1		LSB	
Positive Gain Error Match		±0.5		LSB	
Zero Code Error		±3		LSB	
Zero Code Error Match		±0.5		LSB	
Negative Gain Error		±1		LSB	
Negative Gain Error Match		±0.5		LSB	
CONVERSION RATE					
Conversion Time ²		3		μs	
Autocycle Update Rate ²		50		μs	
Throughput Rate			22.22	kSPS	$f_{SCL} = 400\text{ kHz}$
ANALOG INPUT ³					
Single-Ended Input Range	0		V_{REF}	V	0 V to V_{REF} mode
	0		$2 \times V_{REF}$	V	0 V to $2 \times V_{REF}$ mode
Pseudo Differential Input Range: $V_{IN+} - V_{IN-}$ ⁴	0		V_{REF}		0 V to V_{REF} mode
	0		$2 \times V_{REF}$		0 V to $2 \times V_{REF}$ mode
Fully Differential Input Range: $V_{IN+} - V_{IN-}$	$-V_{REF}$		$+V_{REF}$		0 V to V_{REF} mode
	$-2 \times V_{REF}$		$+2 \times V_{REF}$		0 V to $2 \times V_{REF}$ mode
Input Capacitance ²		30		pF	
DC Input Leakage Current			±1	μA	
DYNAMIC PERFORMANCE					
Signal-to-Noise Ratio (SNR) ¹		73		dB	$f_{IN} = 10\text{ kHz}$ sine wave; differential mode
		72		dB	$f_{IN} = 10\text{ kHz}$ sine wave; single-ended and pseudo differential modes
Signal-to-Noise + Distortion (SINAD) Ratio ¹		71.5		dB	$f_{IN} = 10\text{ kHz}$ sine wave; differential mode
		72.5		dB	$f_{IN} = 10\text{ kHz}$ sine wave; single-ended and pseudo differential modes
Total Harmonic Distortion (THD) ¹		-81		dB	$f_{IN} = 10\text{ kHz}$ sine wave; differential mode
		-79		dB	$f_{IN} = 10\text{ kHz}$ sine wave; single-ended and pseudo differential modes
Spurious-Free Dynamic Range (SFDR) ¹		-81		dB	$f_{IN} = 10\text{ kHz}$ sine wave; differential mode
		-79		dB	$f_{IN} = 10\text{ kHz}$ sine wave; single-ended and pseudo differential modes
Channel-to-Channel Isolation ²			-90	dB	$f_{IN} = 10\text{ kHz to }40\text{ kHz}$

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
TEMPERATURE SENSOR—INTERNAL					
Operating Range	-40		+105	°C	Internal temperature sensor, $T_A = -30^\circ\text{C}$ to $+90^\circ\text{C}$ Internal temperature sensor, $T_A = -40^\circ\text{C}$ to $+105^\circ\text{C}$ LSB size
Accuracy			± 2	°C	
			± 2.5	°C	
Resolution		0.25		°C	
Update Rate		5		ms	
TEMPERATURE SENSOR—EXTERNAL					
Operating Range	-55		+150	°C	External transistor is 2N3906 Limited by external diode $T_A = T_{\text{DIODE}} = -40^\circ\text{C}$ to $+105^\circ\text{C}$ LSB size
Accuracy			± 2	°C	
Resolution		0.25		°C	
Low Level Output Current Source ²		8		μA	
Medium Level Output Current Source ²		32		μA	
High Level Output Current Source ²		128		μA	
Maximum Series Resistance (R_S) for External Diode ²			100	Ω	
Maximum Parallel Capacitance (C_P) for External Diode ²			1	nF	$R_S = 0$, see Figure 30
CURRENT SENSE					
V_{PP} Supply Range	AV_{DD}		59.4	V	$V_{PP} = AV_{DD}$ to 59.4 V
Gain	12.4375	12.5	12.5625		Gain of 12.5 gives a gain error = 0.5% maximum; delivers ± 200 mV range with +2.5 V reference
RS(+)/RS(-) Input Bias Current		25	32	μA	Inputs shorted to V_{PP}
CMRR/PSRR ²		80		dB	
Offset Error		± 50	± 340	μV	
Offset Drift		1		$\mu\text{V}/^\circ\text{C}$	Referred to input
Amplifier Peak-To-Peak Noise ²		400		μV	
V_{PP} Supply Current		0.18	0.25	mA	
REFERENCE					
Reference Output Voltage	2.49		2.51	V	$\pm 0.2\%$ maximum at 25°C only
Reference Input Voltage Range	0.1		4.1	V	For four uncommitted ADCs
	1		$AV_{DD} - 2$		For current sense
DC Leakage Current			± 2	μA	
V_{REF} Output Impedance ²		25		Ω	
Input Capacitance ²		20		pF	
Reference Temperature Coefficient		10	25	ppm/°C	

¹ See the Terminology section for more details.

² Sampled during initial release to ensure compliance, not subject to production testing.

³ V_{IN+} or V_{IN-} must remain within GND/V_{DD} .

⁴ $V_{IN-} = 0$ V for specified performance. For full input range on V_{IN-} , see Figure 40.

GENERAL SPECIFICATIONS

$AV_{DD} = DV_{DD} = 4.5\text{ V to }5.5\text{ V}$, $AGND = DGND = 0\text{ V}$, $V_{REF} = 2.5\text{ V}$ internal or external; $V_{DRIVE} = 2.7\text{ V to }5.5\text{ V}$; $V_{PP} = AV_{DD}$ to 59.4 V ;
 $DAC\ OUTV+ AB$ and $DAC\ OUTV+ CD = 4.5\text{ V to }16.5\text{ V}$; OFFSET IN x is floating, therefore, DAC output span = $0\text{ V to }5\text{ V}$;
 $T_A = -40^\circ\text{C to }+105^\circ\text{C}$, unless otherwise noted.

Table 3.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
LOGIC INPUTS					
Input High Voltage, V_{IH}	$0.7 V_{DRIVE}$			V	SDA, SCL only
Input Low Voltage, V_{IL}			$0.3 V_{DRIVE}$	V	SDA, SCL only
Input Leakage Current, I_{IN}			± 1	μA	
Input Hysteresis, V_{HYST}	$0.05 V_{DRIVE}$			V	
Input Capacitance, C_{IN}		8		pF	
Glitch Rejection		50		ns	Input filtering suppresses noise spikes of less than 50 ns
I ² C Address Pins Maximum External Capacitance if Floating			30	pF	Tristate input
LOGIC OUTPUTS					
SDA, ALERT					
Output Low Voltage, V_{OL}			0.4	V	$I_{SINK} = 3\text{ mA}$
			0.6	V	$I_{SINK} = 6\text{ mA}$
Floating-State Leakage Current			± 1	μA	
Floating-State Output Capacitance		8		pF	
I_{SENSE} OVERRANGE					
Output High Voltage, V_{OH}			$V_{DRIVE} - 0.2$	V	I _{SENSE} OVERRANGE is a push-pull output
Output Low Voltage, V_{OL}			0.2	V	$I_{SOURCE} = 200\text{ }\mu\text{A}$ for push-pull outputs
Overrange Setpoint	V_{FS}	$V_{FS} \times 1.2$		mV	$I_{SINK} = 200\text{ }\mu\text{A}$ for push-pull outputs $V_{FS} = \pm V_{REF} \text{ ADC}/12.5$
POWER REQUIREMENTS					
V_{PP}	AV_{DD}		59.4	V	
AV_{DD}	4.5		5.5	V	
V(+)	4.5		16.5	V	
DV_{DD}	4.5		5.5	V	Tie DV_{DD} to AV_{DD}
V_{DRIVE}	2.7		5.5	V	
I_{DD} Dynamic		5.3	6.5	mA	$AV_{DD} + DV_{DD} + V_{DRIVE}$, DAC outputs unloaded
DAC OUTV+ x, I_{DD}		0.6	1.2	mA	At midscale output voltage, DAC outputs unloaded
Power Dissipation		70	105	mW	
Power-Down					
I_{DD}		0.5	1	μA	For each AV_{DD} and V_{DRIVE}
DI_{DD}		1	16.5	μA	
DAC OUTV+ x, I_{DD}		35	60	μA	
Power Dissipation			2.5	mW	

TIMING CHARACTERISTICS

I²C Serial Interface

AV_{DD} = DV_{DD} = 4.5 V to 5.5 V, AGND = DGND = 0 V, V_{REF} = 2.5 V internal or external; V_{DRIVE} = 2.7 V to 5.5 V; V_{PP} = AV_{DD} to 59.4 V; DAC OUTV+ AB and DAC OUTV+ CD = 4.5 V to 16.5 V; OFFSET IN x is floating, therefore, DAC output span = 0 V to 5 V; T_A = -40°C to +105°C, unless otherwise noted.

Table 4.

Parameter ¹	Limit at T _{MIN} , T _{MAX}	Unit	Description
f _{SCL}	400	kHz max	SCL clock frequency
t ₁	2.5	μs min	SCL cycle time
t ₂	0.6	μs min	t _{HIGH} , SCL high time
t ₃	1.3	μs min	t _{LOW} , SCL low time
t ₄	0.6	μs min	t _{HD,STA} , start/repeated start condition hold time
t ₅	100	ns min	t _{SU,DAT} , data setup time
t ₆	0.9	μs max	t _{HD,DAT} , data hold time
	0	μs min	t _{HD,DAT} , data hold time
t ₇	0.6	μs min	t _{SU,STA} , setup time for repeated start
t ₈	0.6	μs min	t _{SU,STO} , stop condition setup time
t ₉	1.3	μs min	t _{BUF} , bus free time between a stop and a start condition
t ₁₀	300	ns max	t _R , rise time of SCL and SDA when receiving
	0	ns min	t _R , rise time of SCL and SDA when receiving (CMOS compatible)
t ₁₁	300	ns max	t _F , fall time of SDA when transmitting
	0	ns min	t _F , fall time of SDA when receiving (CMOS compatible)
	300	ns max	t _F , fall time of SCL and SDA when receiving
	20 + 0.1C _b ²	ns min	t _F , fall time of SCL and SDA when transmitting
C _b	400	pF max	Capacitive load for each bus line

¹ See Figure 2.

² C_b is the total capacitance in pF of one bus line. t_R and t_F are measured between 0.3 DV_{DD} and 0.7 DV_{DD}.

Timing and Circuit Diagrams

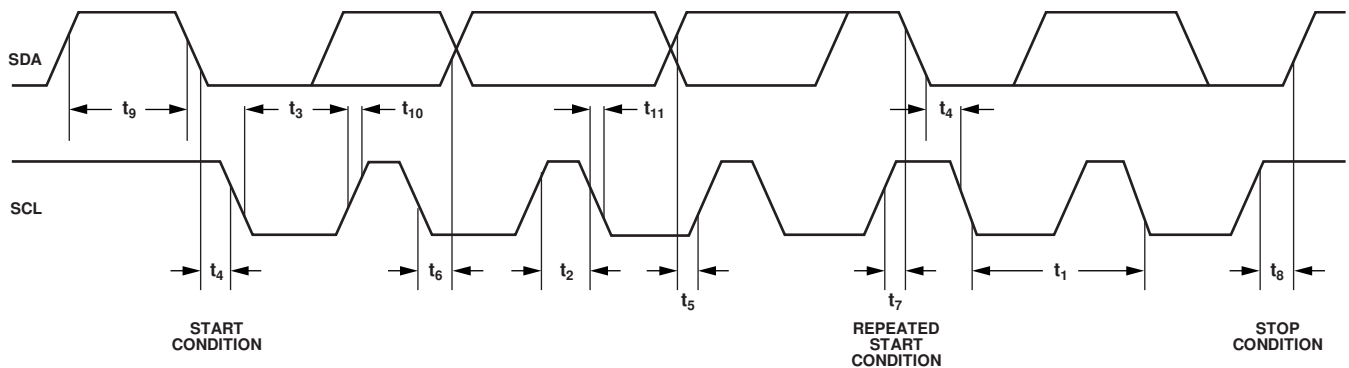


Figure 2. I²C-Compatible Serial Interface Timing Diagram

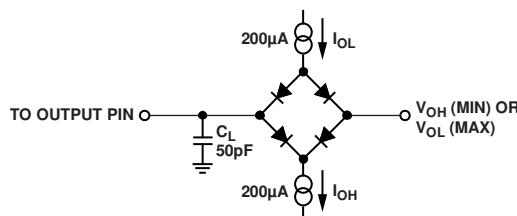


Figure 3. Load Circuit for Digital Output

ABSOLUTE MAXIMUM RATINGS

$T_A = 25^\circ\text{C}$, unless otherwise noted.¹

Table 5.

Parameter	Rating
V_{PPX} to AGND	-0.3 V to +70 V
AV_{DDX} to AGND	-0.3 V to +7 V
DAC OUTV+ AB to AGND	-0.3 V to +17 V
DAC OUTV+ CD to AGND	-0.3 V to +17 V
DV_{DD} to DGND	-0.3 V to +7 V
V_{DRIVE} to OPGND	-0.3 V to +7 V
Digital Inputs to OPGND	-0.3 V to $V_{DRIVE} + 0.3$ V
SDA/SCL to OPGND	-0.3 V to +7 V
Digital Outputs to OPGND	-0.3 V to $V_{DRIVE} + 0.3$ V
RS(+)/RS(-) to V_{PPX}	$V_{PP} - 0.3$ V to $V_{PP} + 0.3$ V
REF _{OUT} /REF _{IN} ADC to AGND	-0.3 V to $AV_{DD} + 0.3$ V
REF _{OUT} /REF _{IN} DAC to AGND	-0.3 V to $AV_{DD} + 0.3$ V
OPGND to AGND	-0.3 V to +0.3 V
OPGND to DGND	-0.3 V to +0.3 V
AGND to DGND	-0.3 V to +0.3 V
V_{OUTX} to AGND	-0.3 V to DAC OUTV(+) + 0.3 V
Analog Inputs to AGND	-0.3 V to $AV_{DD} + 0.3$ V
Operating Temperature Range B Version	-40°C to +105°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature (T_J Max)	150°C
ESD Human Body Model	1 kV
Reflow Soldering Peak Temperature	260°C

¹ Transient currents of up to 100 mA do not cause SCR latch-up.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

To conform with IPC 2221 industrial standards, it is advisable to use conformal coating on the high voltage pins.

THERMAL RESISTANCE

Table 6. Thermal Resistance

Package Type	θ_{JA}	θ_{JC}	Unit
64-Lead TQFP	54	16	°C/W
56-Lead LFCSP	21	2	°C/W

ESD CAUTION



ESD (electrostatic discharge) sensitive device.

Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

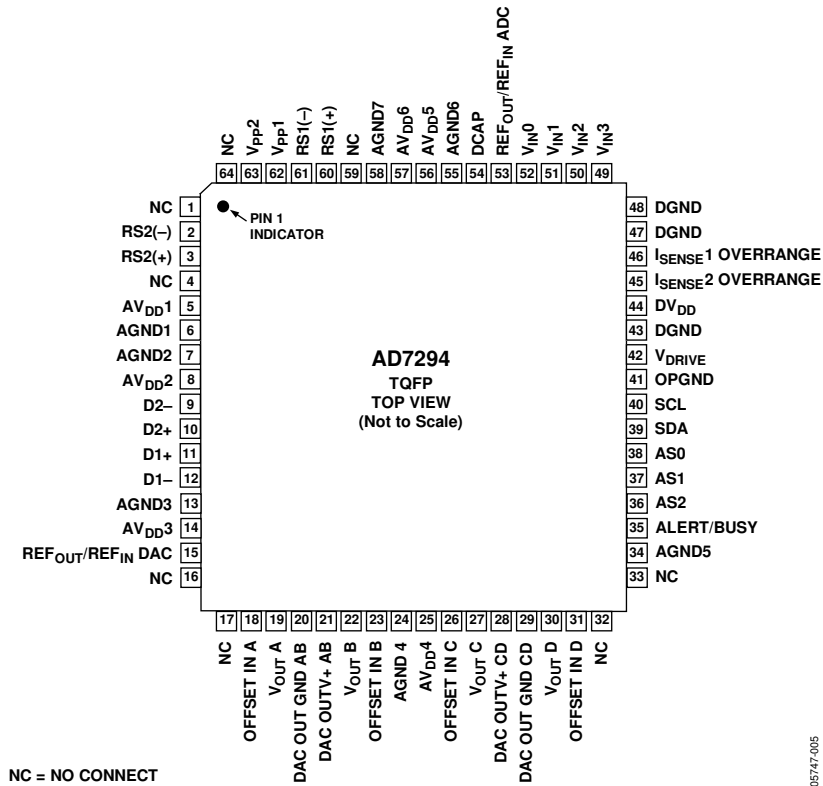
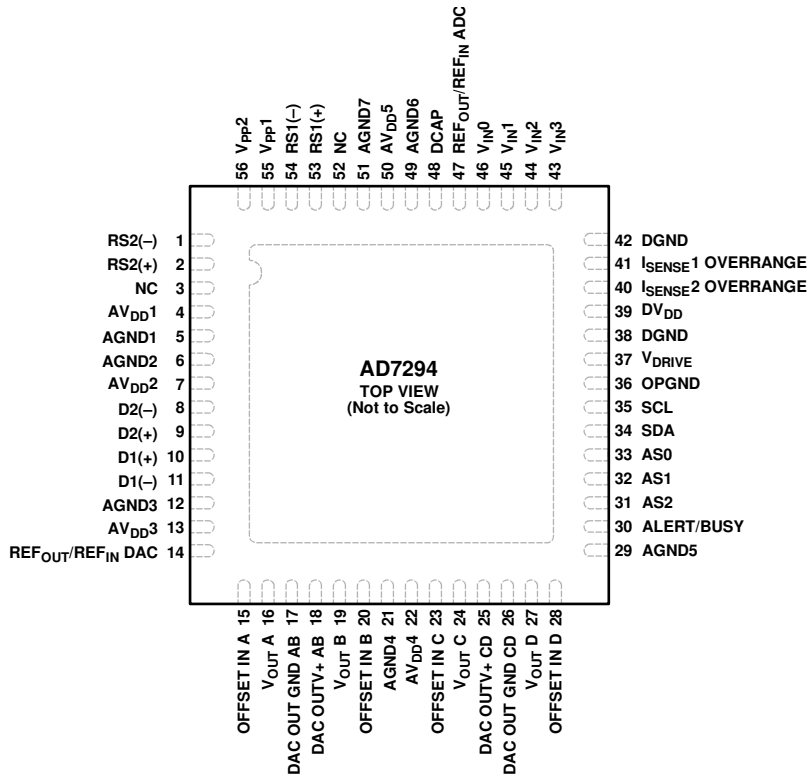


Figure 4. TQFP Pin Configuration



- NOTES
1. NC = NO CONNECT.
 2. CONNECT THE EXPOSED PAD TO THE GROUND PLANE OF THE PCB USING MULTIPLE VIAS.

Figure 5. LFCSP Pin Configuration

Table 7. Pin Function Descriptions

TQFP Pin No.	LFCSP Pin No.	Mnemonic	Description
2, 61	1, 54	RS2(-), RS1(-)	Connection for External Shunt Resistor.
3, 60	2, 53	RS2(+), RS1(+)	Connection for External Shunt Resistor.
1, 4, 16, 17, 32, 33, 59, 64	3, 52	NC	No Connection. Do not connect these pins.
5, 8, 14, 25, 56, 57	4, 7, 13, 22, 50	AV _{DD1} to AV _{DD6} for TQFP; AV _{DD1} to AV _{DD4} for LFCSP	Analog Supply Pins. The operating range is 4.5 V to 5.5 V. These pins provide the supply voltage for all the analog circuitry on the AD7294. Connect the AV _{DD} and DV _{DD} pins together to ensure that all supply pins are at the same potential. This supply should be decoupled to AGND with one 10 μ F tantalum capacitor and a 0.1 μ F ceramic capacitor for each AV _{DD} pin.
6, 7, 13, 24, 34, 55, 58	5, 6, 12, 21, 29, 49, 51	AGND1 to AGND7	Analog Ground. Ground reference point for all analog circuitry on the AD7294. Refer all analog input signals and any external reference signal to this AGND voltage. Connect all seven of these AGND pins to the AGND plane of the system. Note that AGND5 is a DAC ground reference point and should be used as a star ground for circuitry being driven by the DAC outputs. Ideally, the AGND and DGND voltages should be at the same potential and must not be more than 0.3 V apart, even on a transient basis.
9, 12	8, 11	D2(-), D1(-)	Temperature Sensor Analog Input. These pins are connected to the external temperature sensing transistor. See Figure 46 and Figure 47.
10, 11	9, 10	D2(+), D1(+)	Temperature Sensor Analog Input. These pins are connected to the external temperature sensing transistor. See Figure 46 and Figure 47.
15	14	REF _{OUT} /REF _{IN} DAC	DAC Reference Output/Input Pin. The REF _{OUT} /REF _{IN} DAC pin is common to all four DAC channels. On power-up, the default configuration of this pin is external reference (REF _{IN}). Enable the internal reference by writing to the power-down register; see Table 27. Decoupling capacitors (220 nF recommended) are connected to this pin to decouple the reference buffer. Provided the output is buffered, the on-chip reference can be taken from this pin and applied externally to the rest of a system. A maximum external reference voltage of AV _{DD} - 2 V can be supplied to the REF _{OUT} portion of the REF _{OUT} /REF _{IN} DAC pin.
18, 23, 26, 31	15, 20, 23, 28	OFFSET IN A to OFFSET IN D	DAC Analog Offset Input Pins. These pins set the desired output range for each DAC channel. The DACs have an output voltage span of 5 V, which can be shifted from 0 V to 5 V to a maximum output voltage of 10 V to 15 V by supplying an offset voltage to these pins. These pins can be left floating, in which case decouple them to AGND with a 100 nF capacitor.
19, 22, 27, 30	16, 19, 24, 27	V _{OUT} A to V _{OUT} D	Buffered Analog DAC Outputs for Channel A to Channel D. Each DAC analog output is driven from an output amplifier that can be offset using the OFFSET IN x pin. The DAC has a maximum output voltage span of 5 V that can be level shifted to a maximum output voltage level of 15 V. Each output is capable of sourcing and sinking 10 mA and driving a 10 nF load.
20, 29	17, 26	DAC OUT GND AB, DAC OUT GND CD	Analog Ground. Analog ground pins for the DAC output amplifiers on V _{OUT} A and V _{OUT} B, and V _{OUT} C and V _{OUT} D, respectively.
21, 28	18, 25	DAC OUTV+ AB, DAC OUTV+ CD	Analog Supply. Analog supply pins for the DAC output amplifiers on V _{OUT} A and V _{OUT} B, and V _{OUT} C and V _{OUT} D, respectively. The operating range is 4.5 V to 16.5 V.
35	30	ALERT/BUSY	Digital Output. Selectable as an alert or busy output function in the configuration register. This is an open-drain output. An external pull-up resistor is required. When configured as an alert, this pin acts as an out-of-range indicator and becomes active when the conversion result violates the DATA _{HIGH} or DATA _{LOW} register values. See the Alert Status Registers section. When configured as a busy output, this pin becomes active when a conversion is in progress.
38, 37, 36	33, 32, 31	AS0, AS1, AS2	Digital Logic Input. Together, the logic state of these inputs selects a unique I ² C address for the AD7294. See Table 34 for details.
39	34	SDA	Digital Input/Output. Serial bus bidirectional data; external pull-up resistor required.

TQFP Pin No.	LFCSP Pin No.	Mnemonic	Description
40	35	SCL	Serial I ² C Bus Clock. The data transfer rate in I ² C mode is compatible with both 100 kHz and 400 kHz operating modes. Open-drain input; external pull-up resistor required.
41	36	OPGND	Dedicated Ground Pin for I ² C Interface.
42	37	V _{DRIVE}	Logic Power Supply. The voltage supplied at this pin determines at what voltage the interface operates. Decouple this pin to DGND. The voltage range on this pin is 2.7 V to 5.5 V and may be different to the voltage level at AV _{DD} and DV _{DD} , but should never exceed either by more than 0.3 V. To set the input and output thresholds, connect this pin to the supply to which the I ² C bus is pulled.
43, 47, 48	38, 42	DGND	Digital Ground. This pin is the ground for all digital circuitry.
44	39	DV _{DD}	Logic Power Supply. The operating range is 4.5 V to 5.5 V. These pins provide the supply voltage for all the digital circuitry on the AD7294. Connect the AV _{DD} and DV _{DD} pins together to ensure that all supply pins are at the same potential. Decouple this supply to DGND with a 10 µF tantalum capacitor and a 0.1 µF ceramic capacitor.
46, 45	41, 40	I _{SENSE1} OVERRANGE, I _{SENSE2} OVERRANGE	Fault Comparator Outputs. These pins connect to the high-side current sense amplifiers.
49, 50, 51, 52	43, 44, 45, 46	V _{IN3} to V _{IN0}	Uncommitted ADC Analog Inputs. These pins are programmable as four single-ended channels or two true differential analog input channel pairs. See Table 1 and Table 13 for more details.
53	47	REF _{OUT} /REF _{IN} ADC	ADC Reference Input/Output Pin. The REF _{OUT} /REF _{IN} ADC pin provides the reference source for the ADC. Upon power-up, the default configuration of this pin is external reference (REF _{IN}). Enable the internal reference by writing to the power-down register; see Table 27. Connect decoupling capacitors (220 nF recommended) to this pin to decouple the reference buffer. Provided the output is buffered, the on-chip reference can be taken from this pin and applied externally to the rest of a system. A maximum external reference voltage of 2.5 V can be supplied to the REF _{OUT} portion of the REF _{OUT} /REF _{IN} ADC pin.
54	48	DCAP	External Decoupling Capacitor Input for Internal Temperature Sensor. Decouple this pin to AGND using a 0.1 µF capacitor. In normal operation, the voltage is typically 3.7 V.
62, 63	55, 56	V _{PP1} , V _{PP2}	Current Sensor Supply Pins. Power supply pins for the high-side current sense amplifiers. Operating range is from AV _{DD} to 59.4 V. Decouple this supply to AGND. See the Current Sense Filtering section.
N/A ¹	0	EPAD	The exposed pad is located on the underside of the package. Connect the exposed pad to the ground plane of the PCB using multiple vias.

¹ N/A means not applicable.

TYPICAL PERFORMANCE CHARACTERISTICS

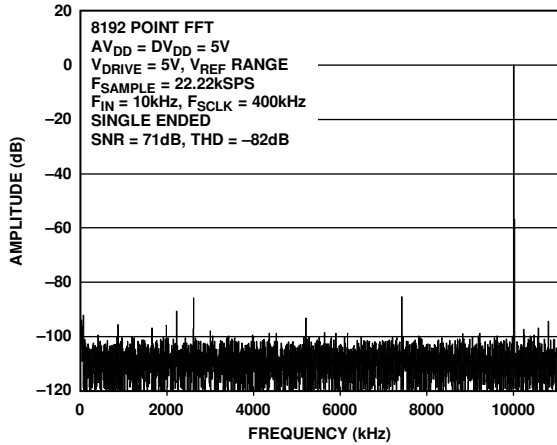


Figure 6. Signal-to-Noise Ratio Single-Ended, V_{REF} Range

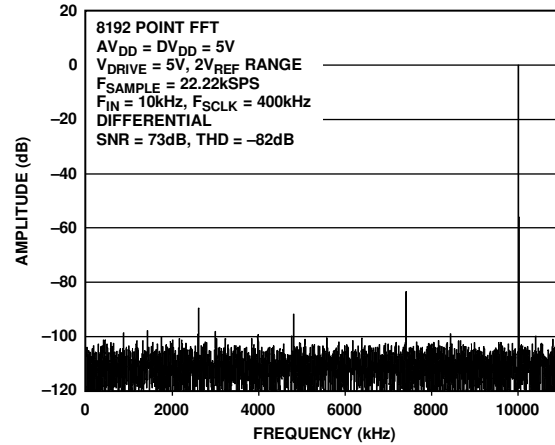


Figure 9. Signal-to-Noise Ratio Differential, 2 × V_{REF} Range

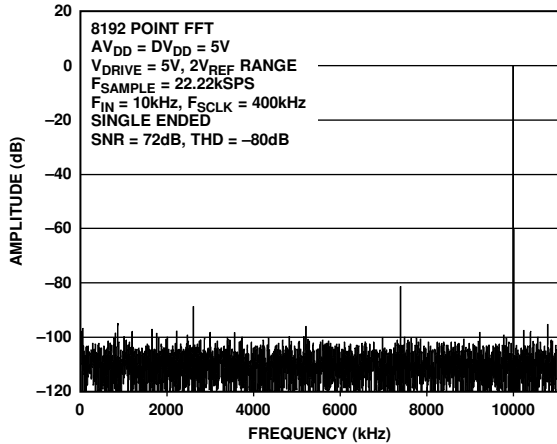


Figure 7. Signal-to-Noise Ratio Single-Ended, 2 × V_{REF} Range

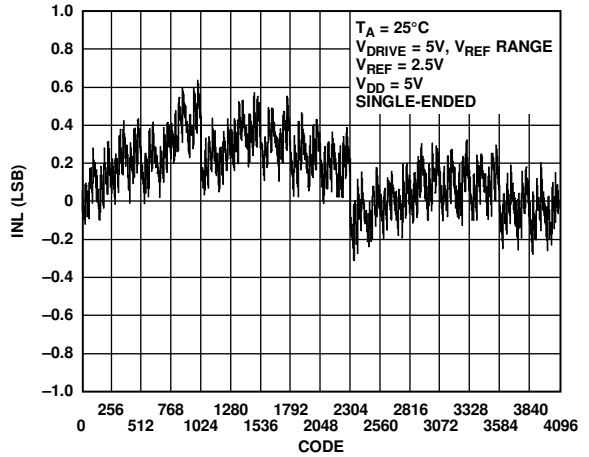


Figure 10. ADC INL Single-Ended, V_{REF} Range

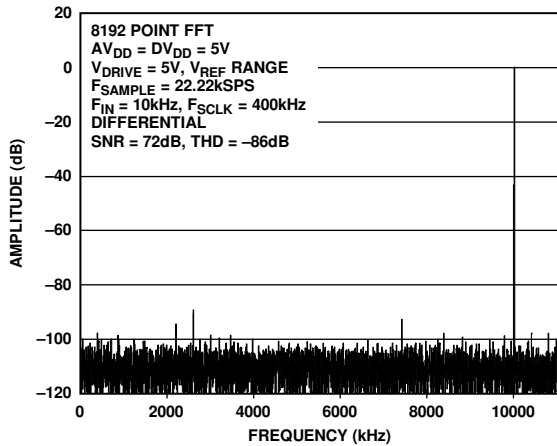


Figure 8. Signal-to-Noise Ratio Differential, V_{REF} Range

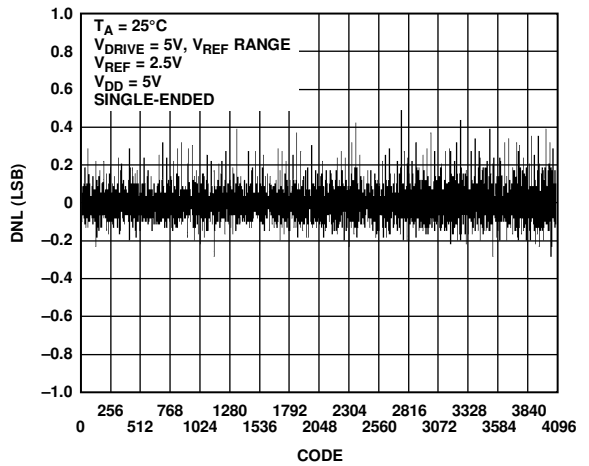


Figure 11. ADC DNL Single-Ended, V_{REF} Range

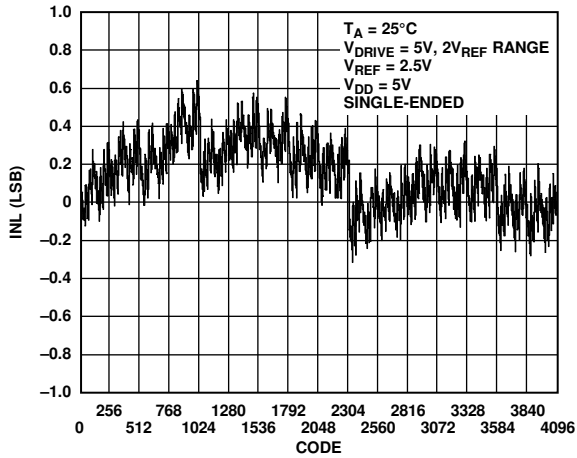


Figure 12. ADC INL Single-Ended, $2 \times V_{REF}$ Range

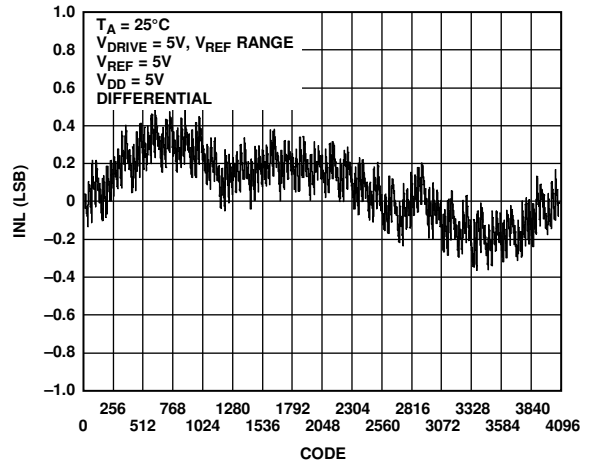


Figure 15. ADC INL Differential, V_{REF} Range

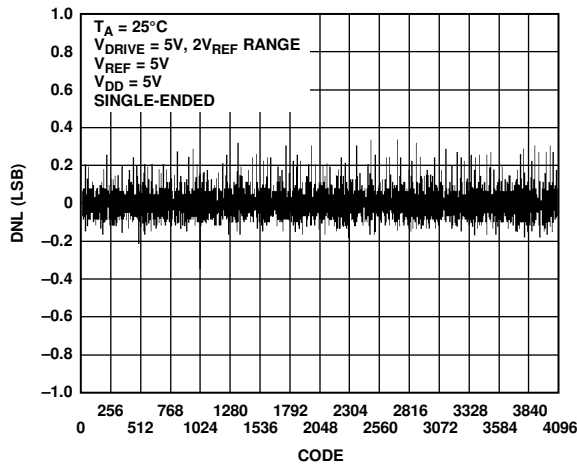


Figure 13. ADC DNL Single-Ended, $2 \times V_{REF}$ Range

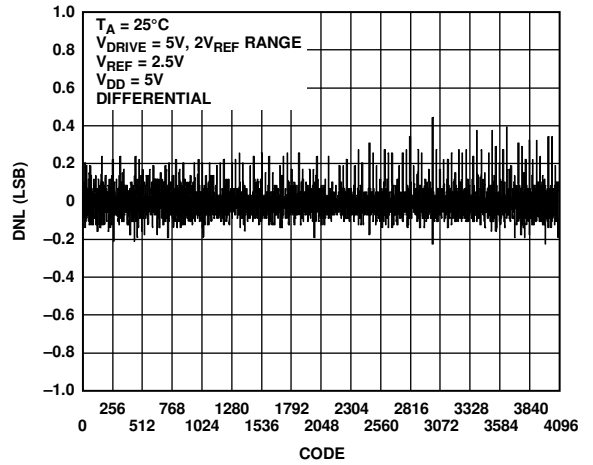


Figure 16. ADC DNL Differential, $2 \times V_{REF}$ Range

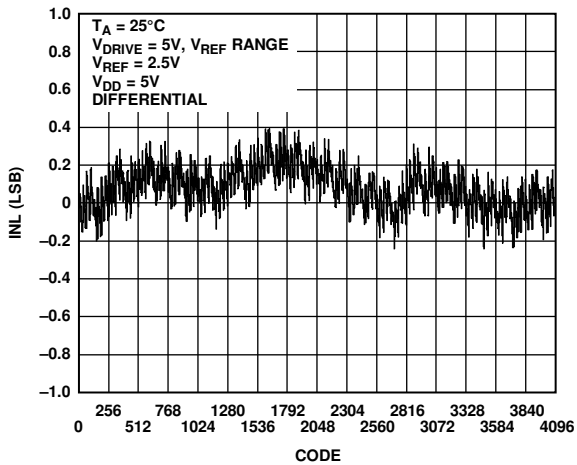


Figure 14. ADC INL Differential, V_{REF} Range

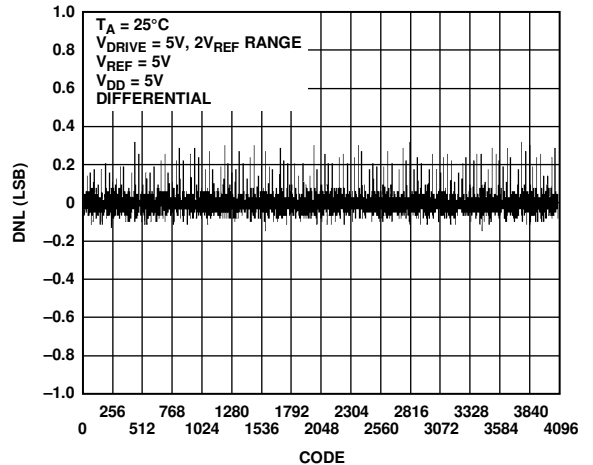


Figure 17. ADC DNL Differential, $2 \times V_{REF}$ Range

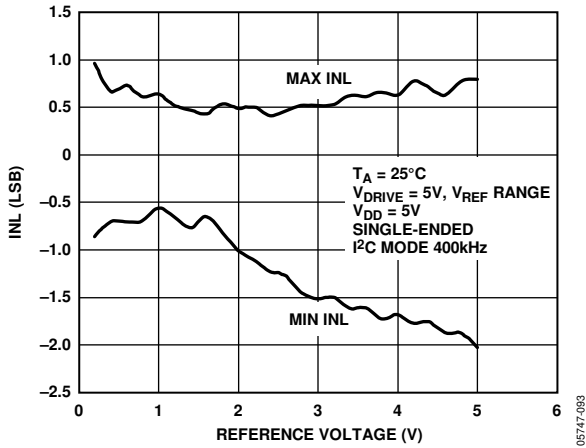


Figure 18. ADC INL vs. Reference Voltage

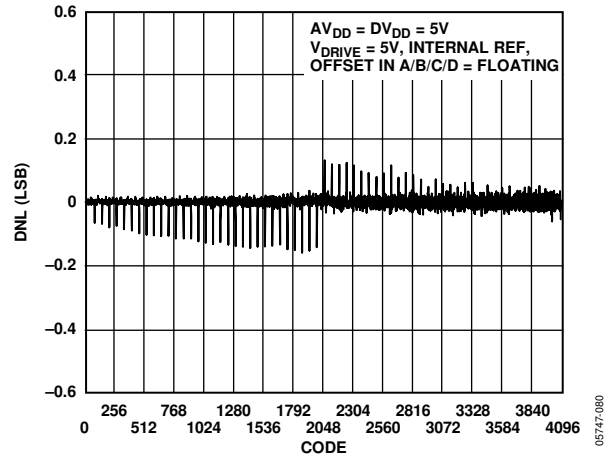


Figure 21. DAC DNL

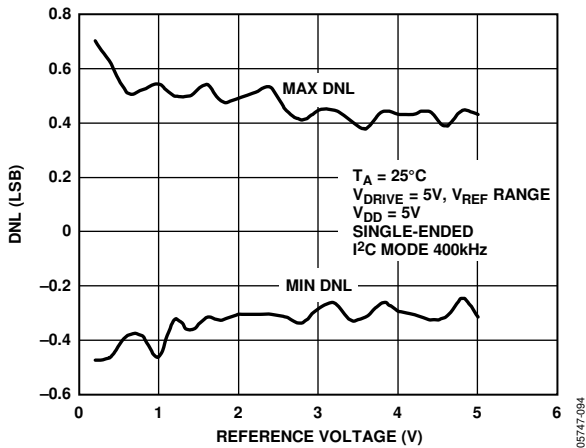


Figure 19. ADC DNL vs. Reference Voltage

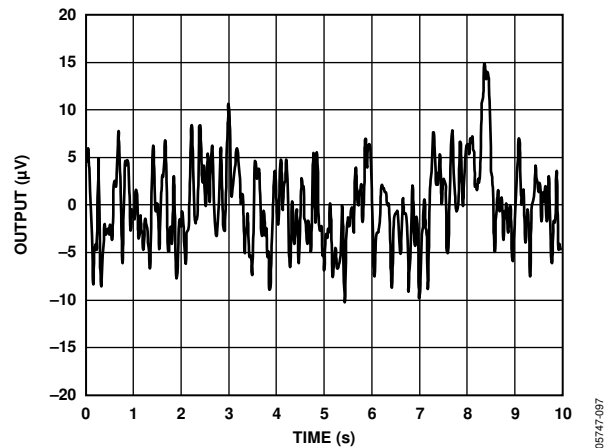


Figure 22. 0.1 Hz to 10 Hz DAC Output Noise (Code 800)

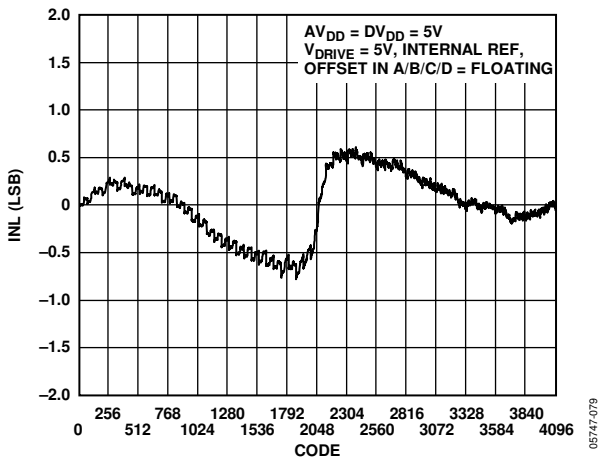


Figure 20. DAC INL

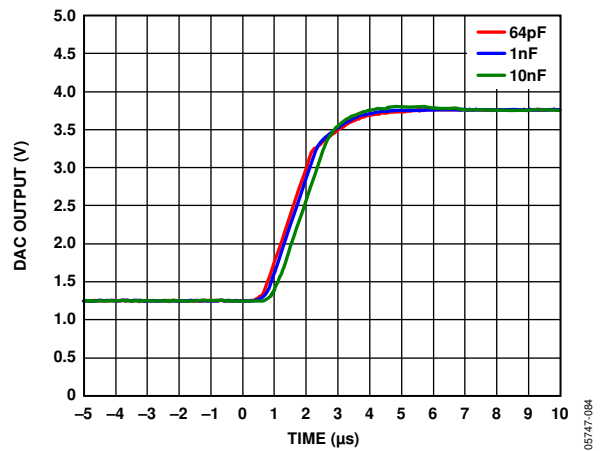


Figure 23. Settling Time for a 1/4 to 3/4 Output Voltage Step

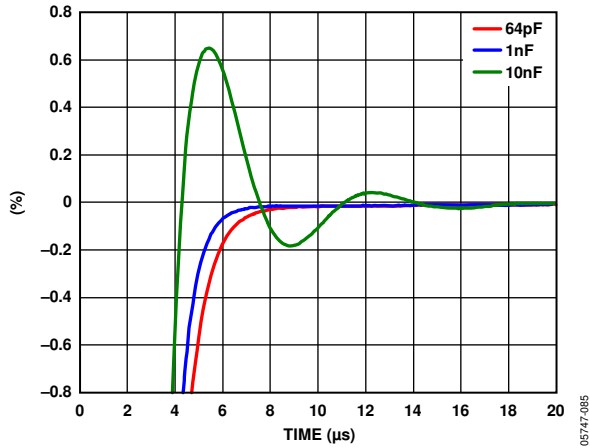


Figure 24. Zoomed in Settling for a 1/4 to 3/4 Output Voltage Step

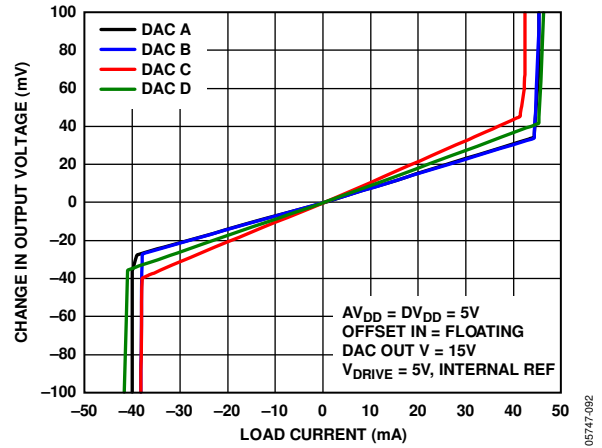


Figure 27. DAC Output Voltage vs. Load Current, Input Code = x800

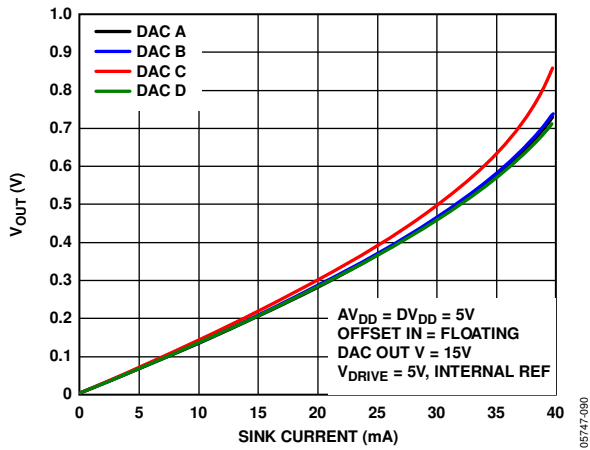


Figure 25. DAC Sinking Current at Input Code = x000, ($V_{OUT} = 0V$)

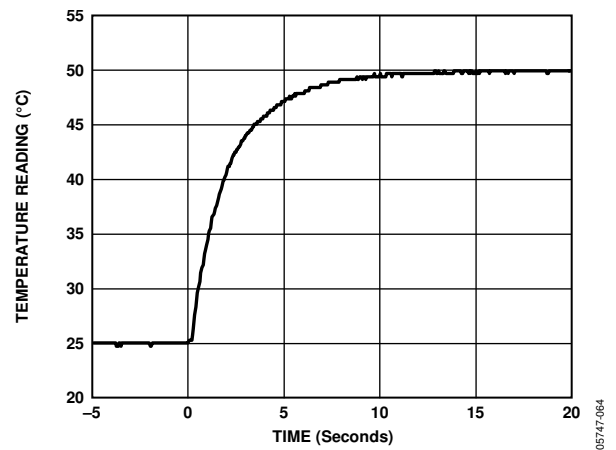


Figure 28. Response of the AD7294 to Thermal Shock Using 2N3906 (2N3906 Placed in a Stirred Oil Bath)

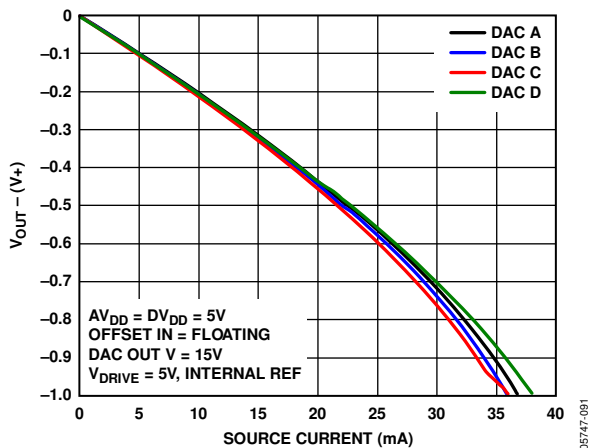


Figure 26. DAC Sourcing Current at Input Code = x000, ($V_{OUT} = 0V$)

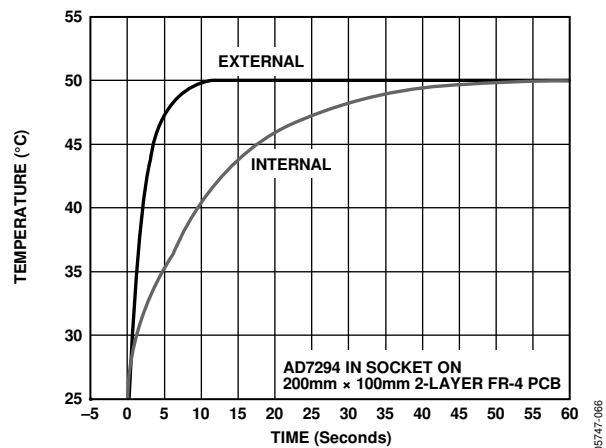


Figure 29. Response to Thermal Shock from Room Temperature into 50°C Stirred Oil (Both the AD7294 and the 2N3906 are Placed in a Stirred Oil Bath)

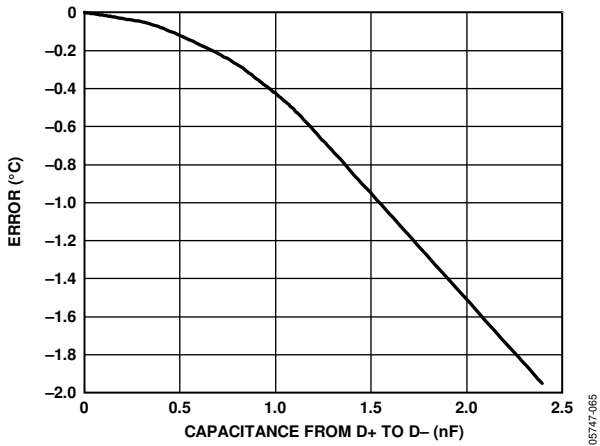


Figure 30. Temperature Error vs. Capacitor Between D+ and D-

05747-065

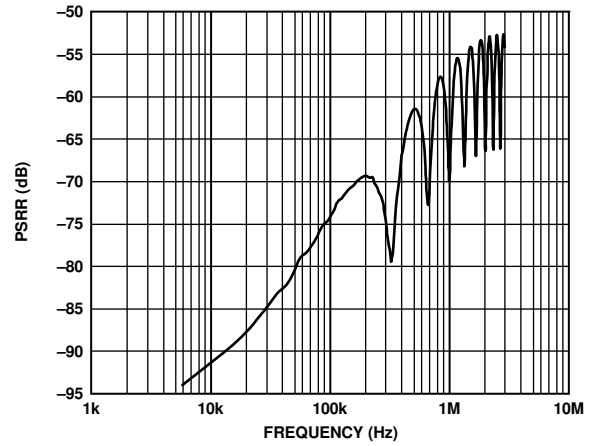


Figure 33. I_{SENSE} Power Supply Rejection Ratio vs. Supply Ripple Frequency Without V_{PP} Supply Decoupling Capacitors for a 500 mV Ripple

05747-102

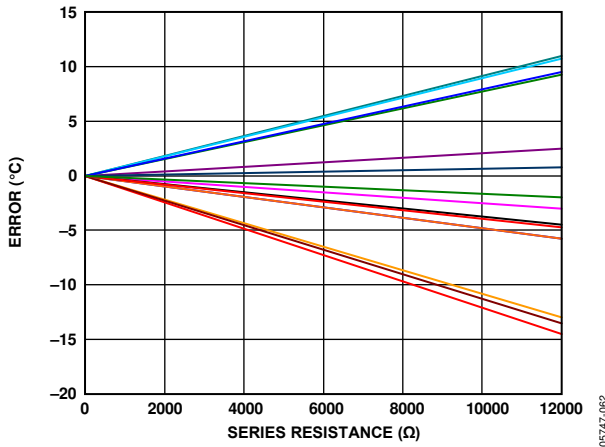


Figure 31. Temperature Error vs. Series Resistance for 15 Typical Devices

05747-062

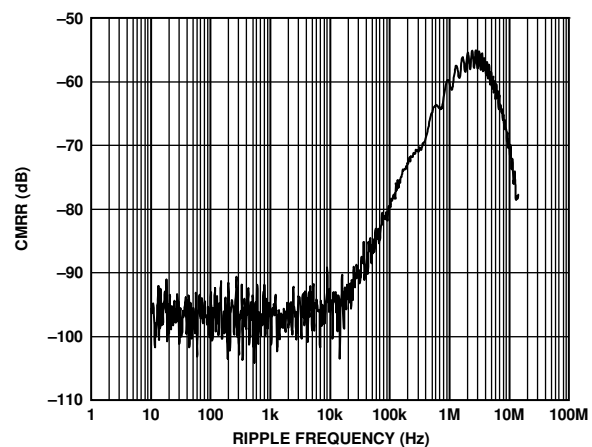


Figure 34. I_{SENSE} Common-Mode Rejection Ratio vs. Ripple Frequency for a 400 mV Peak-To-Peak Ripple

05747-103

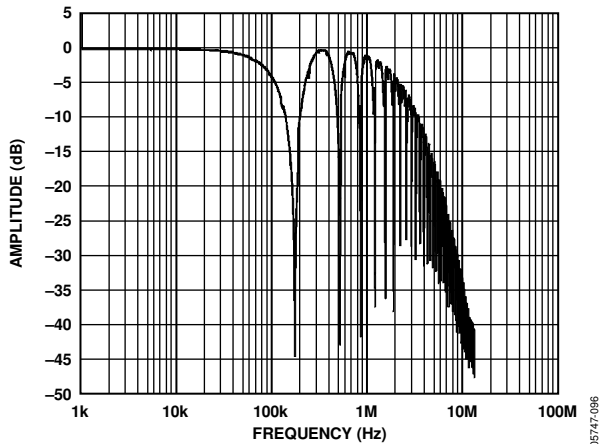


Figure 32. Frequency Response of the High-Side Current Sensor on the AD7294

05747-096

TERMINOLOGY

DAC TERMINOLOGY

Relative Accuracy

For the DAC, relative accuracy or integral nonlinearity (INL) is a measure of the maximum deviation, in LSBs, from a straight line passing through the endpoints of the DAC transfer function.

Differential Nonlinearity

Differential nonlinearity (DNL) is the difference between the measured change and the ideal 1 LSB change between any two adjacent codes. A specified differential nonlinearity of ± 1 LSB maximum ensures monotonicity. This DAC is guaranteed monotonic by design.

Zero Code Error

Zero code error is a measure of the output error when zero code (0x0000) is loaded to the DAC register. Ideally, the output should be 0 V. The zero code error is always positive in the AD7294 because the output of the DAC cannot go below 0 V. Zero code error is expressed in mV.

Full-Scale Error

Full-scale error is a measure of the output error when full-scale code (0xFFFF) is loaded to the DAC register. Ideally, the output should be $V_{DD} - 1$ LSB. Full-scale error is expressed in mV.

Gain Error

Gain error is a measure of the span error of the DAC. It is the deviation in slope of the DAC transfer characteristic from ideal, expressed as a percent of the full-scale range.

Total Unadjusted Error

Total unadjusted error (TUE) is a measure of the output error, taking all of the various errors into account.

Zero Code Error Drift

Zero code error drift is a measure of the change in zero code error with a change in temperature. It is expressed in $\mu\text{V}/^\circ\text{C}$.

Gain Error Drift

Gain error drift is a measure of the change in gain error with changes in temperature. It is expressed in (ppm of full-scale range)/ $^\circ\text{C}$.

ADC TERMINOLOGY

Signal-to-Noise and Distortion Ratio (SINAD)

The measured ratio of signal-to-noise and distortion at the output of the ADC. The signal is the rms amplitude of the fundamental. Noise is the sum of all nonfundamental signals up to half the sampling frequency ($f_s/2$), excluding dc. The

ratio is dependent on the number of quantization levels in the digitization process; the more levels, the smaller the quantization noise. The theoretical signal-to-noise and distortion ratio for an ideal N-bit converter with a sine wave input is given by

$$\text{Signal-to-(Noise + Distortion)} = (6.02N + 1.76) \text{ dB}$$

Thus, the SINAD is 74 dB for an ideal 12-bit converter.

Total Harmonic Distortion (THD)

The ratio of the rms sum of harmonics to the fundamental. For the AD7294, it is defined as

$$\text{THD(dB)} = 20 \log \frac{\sqrt{V_2^2 + V_3^2 + V_4^2 + V_5^2 + V_6^2}}{V_1}$$

where V_1 is the rms amplitude of the fundamental and V_2 , V_3 , V_4 , V_5 , and V_6 are the rms amplitudes of the second through sixth harmonics.

Peak Harmonic or Spurious Noise

The ratio of the rms value of the next largest component in the ADC output spectrum (up to $f_s/2$ and excluding dc) to the rms value of the fundamental. Typically, the value of this specification is determined by the largest harmonic in the spectrum, but for ADCs where the harmonics are buried in the noise floor, it is a noise peak.

Integral Nonlinearity

The maximum deviation from a straight line passing through the endpoints of the ADC transfer function. The endpoints are zero scale, a point 1 LSB below the first code transition, and full scale, a point 1 LSB above the last code transition.

Differential Nonlinearity

The difference between the measured and the ideal 1 LSB change between any two adjacent codes in the ADC.

Offset Error

The deviation of the first code transition (00...000) to (00...001) from the ideal—that is, AGND + 1 LSB.

Offset Error Match

The difference in offset error between any two channels.

Gain Error

The deviation of the last code transition (111...110) to (111...111) from the ideal (that is, $\text{REF}_{IN} - 1$ LSB) after the offset error has been adjusted out.

Gain Error Match

The difference in gain error between any two channels.

THEORY OF OPERATION

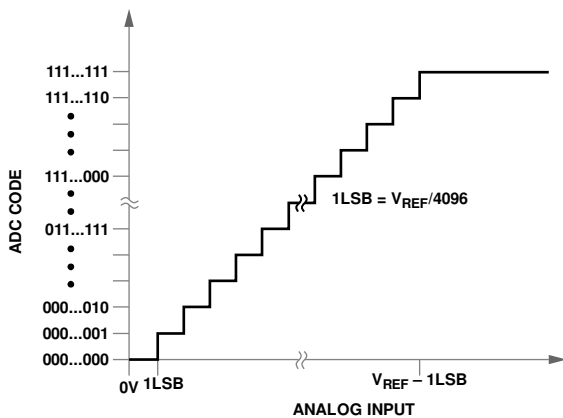
ADC OVERVIEW

The AD7294 provides the user with a 9-channel multiplexer, an on-chip track-and-hold, and a successive approximation ADC based around a capacitive DAC. The analog input range for the device can be selected as a 0 V to V_{REF} input or a $2 \times V_{REF}$ input, configured with either single-ended or differential analog inputs. The AD7294 has an on-chip 2.5 V reference that can be disabled when an external reference is preferred. If the internal ADC reference is to be used elsewhere in a system, the output must first be buffered.

The various monitored and uncommitted input signals are multiplexed into the ADC. The AD7294 has four uncommitted analog input channels, V_{IN0} to V_{IN3} . These four channels allow single-ended, differential, and pseudo differential mode measurements of various system signals.

ADC TRANSFER FUNCTIONS

The designed code transitions occur at successive integer LSB values (1 LSB, 2 LSB, and so on). In single-ended mode, the LSB size is $V_{REF}/4096$ when the 0 V to V_{REF} range is used and $2 \times V_{REF}/4096$ when the 0 V to $2 \times V_{REF}$ range is used. The ideal transfer characteristic for the ADC when outputting straight binary coding is shown in Figure 35.



NOTE

- V_{REF} IS EITHER V_{REF} OR $2 \times V_{REF}$.

Figure 35. Single-Ended Transfer Characteristic

In differential mode, the LSB size is $2 \times V_{REF}/4096$ when the 0 V to V_{REF} range is used, and $4 \times V_{REF}/4096$ when the 0 V to $2 \times V_{REF}$ range is used. The ideal transfer characteristic for the ADC when outputting twos complement coding is shown in Figure 36 (with the $2 \times V_{REF}$ range).

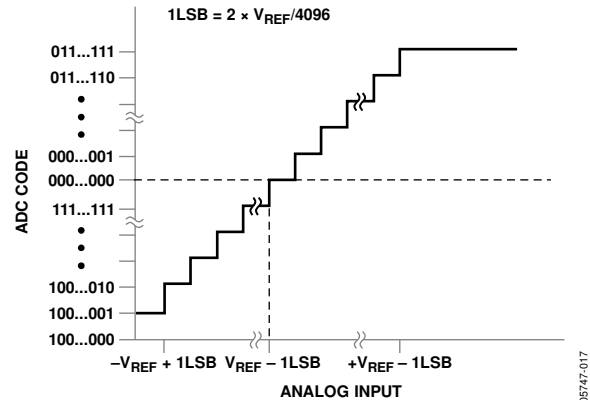


Figure 36. Differential Transfer Characteristic with $V_{REF} \pm V_{REF}$ Input Range

For V_{IN0} to V_{IN3} in single-ended mode, the output code is straight binary, where

$V_{IN} = 0$ V, $D_{OUT} = \text{x000}$, $V_{IN} = V_{REF} - 1$ LSB, and $D_{OUT} = \text{xFFF}$

In differential mode, the code is twos complement, where

$V_{IN+} - V_{IN-} = 0$ V, and $D_{OUT} = \text{x00}$

$V_{IN+} - V_{IN-} = V_{REF} - 1$ LSB, and $D_{OUT} = \text{x7FF}$

$V_{IN+} - V_{IN-} = -V_{REF}$, and $D_{OUT} = \text{x800}$

Channel 5 and Channel 6 (current sensor inputs) are twos complement, where

$V_{IN+} - V_{IN-} = 0$ mV, and $D_{OUT} = \text{x000}$

$V_{IN+} - V_{IN-} = V_{REF}/12.5 - 1$ LSB, $D_{OUT} = \text{x7FF}$

$V_{IN+} - V_{IN-} = -V_{REF}/12.5$, $D_{OUT} = \text{x800}$

Channel 7 to Channel 9 (temperature sensor inputs) are twos complement with the LSB equal to 0.25°C , where

$T_{IN} = 0^\circ\text{C}$, and $D_{OUT} = \text{x000}$

$T_{IN} = +255.75^\circ\text{C}$, and $D_{OUT} = \text{x7FF}$

$T_{IN} = -256^\circ\text{C}$, and $D_{OUT} = \text{x800}$

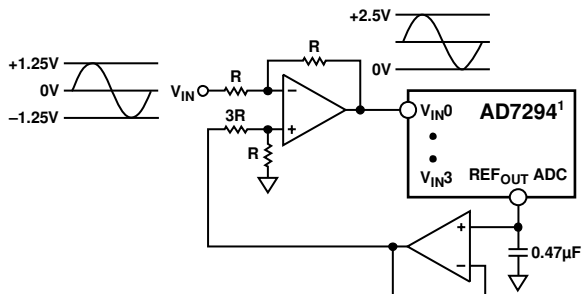
ANALOG INPUTS

The AD7294 has a total of four analog inputs. Depending on the configuration register setup, they can be configured as two single-ended inputs, two pseudo differential channels, or two fully differential channels. See the Register Setting section for further details.

Single-Ended Mode

The AD7294 can have four single-ended analog input channels. In applications where the signal source has high impedance, it is recommended to buffer the analog input before applying it to the ADC. The analog input range can be programmed to be either 0 V to V_{REF} or 0 V to $2 \times V_{REF}$. In $2 \times V_{REF}$ mode, the input is effectively divided by 2 before the conversion takes place. Note that the voltage with respect to GND on the ADC analog input pins cannot exceed AV_{DD} .

If the analog input signal to be sampled is bipolar, the internal reference of the ADC can be used to externally bias up this signal so that it is correctly formatted for the ADC. Figure 37 shows a typical connection diagram when operating the ADC in single-ended mode.

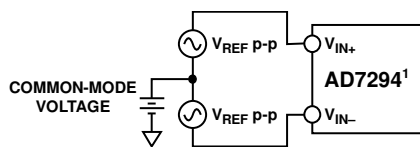


¹ADDITIONAL PINS OMITTED FOR CLARITY.

Figure 37. Single-Ended Mode Connection Diagram

Differential Mode

The AD7294 can have two differential analog input pairs. Differential signals have some benefits over single-ended signals, including noise immunity based on the common-mode rejection of the device and improvements in distortion performance. Figure 38 defines the fully differential analog input of the AD7294.



¹ADDITIONAL PINS OMITTED FOR CLARITY.

Figure 38. Differential Input Definition

The amplitude of the differential signal is the difference between the signals applied to V_{IN+} and V_{IN-} in each differential pair ($V_{IN+} - V_{IN-}$). The resulting converted data is stored in two's complement format in the result register. Simultaneously drive V_{IN0} and V_{IN1} by two signals, each of amplitude V_{REF} (or $2 \times V_{REF}$, depending on the range chosen), that are 180° out of phase. Assuming the 0 V to V_{REF} range is selected, the amplitude of the differential signal is, therefore, $-V_{REF}$ to $+V_{REF}$ peak-to-peak ($2 \times V_{REF}$), regardless of the common mode (V_{CM}).

The common mode is the average of the two signals

$$(V_{IN+} + V_{IN-})/2$$

The common mode is, therefore, the voltage on which the two inputs are centered.

This results in the span of each input being $V_{CM} \pm V_{REF}/2$. This voltage has to be set up externally, and its range varies with the reference value, V_{REF} . As the value of V_{REF} increases, the common-mode range decreases. When driving the inputs with an amplifier, the actual common-mode range is determined by the output voltage swing of the amplifier.

The common mode must be in this range to guarantee the functionality of the AD7294.

When a conversion takes place, the common mode is rejected, resulting in a virtually noise-free signal of amplitude $-V_{REF}$ to $+V_{REF}$, corresponding to the digital output codes of -2048 to $+2047$ in two's complement format.

If the $2 \times V_{REF}$ range is used, the input signal amplitude extends from $-2 \times V_{REF}$ ($V_{IN+} = 0$ V, $V_{IN-} = V_{REF}$) to $+2 \times V_{REF}$ ($V_{IN-} = 0$ V, $V_{IN+} = V_{REF}$).

Driving Differential Inputs

The differential modes available on V_{IN0} to V_{IN3} in Table 13 require that V_{IN+} and V_{IN-} be driven simultaneously with two equal signals that are 180° out of phase. The common mode on which the analog input is centered must be set up externally. The common-mode range is determined by V_{REF} , the power supply, and the particular amplifier used to drive the analog inputs. Differential modes of operation with either an ac or dc input provide the best THD performance over a wide frequency range. Because not all applications have a signal preconditioned for differential operation, there is often a need to perform a single-ended-to-differential conversion.

Using an Op Amp Pair

An op amp pair can be used to directly couple a differential signal to one of the analog input pairs of the AD7294. The circuit configurations illustrated in Figure 39 show how a dual op amp can be used to convert a single-ended bipolar signal into a differential unipolar input signal.

The voltage applied to Point A sets up the common-mode voltage. As shown in Figure 39, Point A connects to the reference, but any value in the common-mode range can be the input at Point A to set up the common mode. The AD8022 is a suitable dual op amp that can be used in this configuration to provide differential drive to the AD7294.

Care is required when choosing the op amp because the selection depends on the required power supply and system performance objectives. The driver circuits in Figure 39 are optimized for dc coupling applications requiring best distortion performance. The differential op amp driver circuit shown in Figure 39 is configured to convert and level shift a single-ended, ground-referenced (bipolar) signal to a differential signal centered at the V_{REF} level of the ADC.

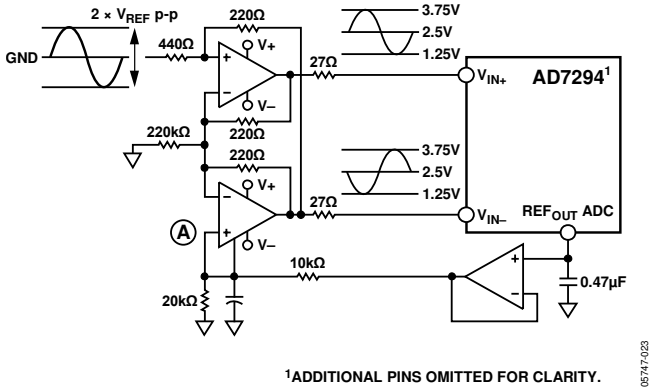


Figure 39. Dual Op Amp Circuit to Convert a Single-Ended Bipolar Signal into a Differential Unipolar Signal

Pseudo Differential Mode

The four uncommitted analog input channels can be configured as two pseudo differential pairs. Uncommitted input, V_{IN0} and V_{IN1} , are a pseudo differential pair, as are V_{IN2} and V_{IN3} . In this mode, V_{IN+} is connected to the signal source, which can have a maximum amplitude of V_{REF} (or $2 \times V_{REF}$, depending on the range chosen) to make use of the full dynamic range of the device. A dc input is applied to V_{IN-} . The voltage applied to this input provides an offset from ground or a pseudo ground for the V_{IN+} input. Which channel is V_{IN+} is determined by the ADC channel allocation. The differential mode must be selected to operate in the pseudo differential mode. The resulting converted pseudo differential data is stored in twos complement format in the result register.

The governing equation for the pseudo differential mode, for V_{IN0} is

$$V_{OUT} = 2(V_{IN+} - V_{IN-}) - V_{REF_ADC}$$

where V_{IN+} is the single-ended signal and V_{IN-} is a dc voltage.

The benefit of pseudo differential inputs is that they separate the analog input signal ground from the ADC ground, allowing dc common-mode voltages to be cancelled. The typical voltage range for V_{IN-} while in pseudo differential mode is shown in Figure 40; Figure 41 shows a connection diagram for pseudo differential mode.

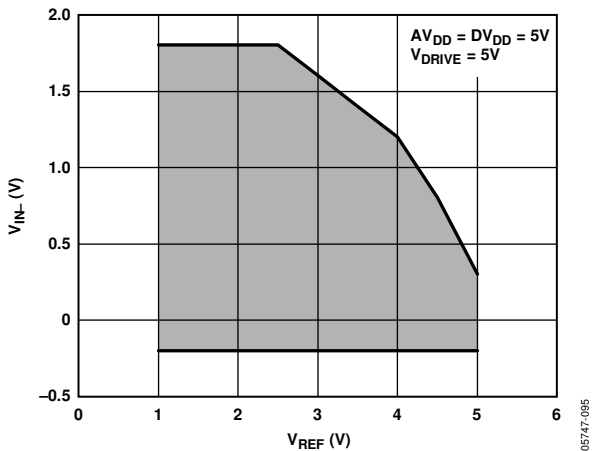


Figure 40. V_{IN-} Input Range vs. V_{REF} in Pseudo Differential Mode

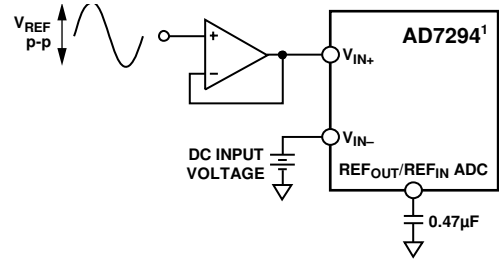


Figure 41. Pseudo Differential Mode Connection Diagram

CURRENT SENSOR

Two bidirectional high-side current sense amplifiers are provided that can accurately amplify differential current shunt voltages in the presence of high common-mode voltages from AV_{DD} up to 59.4 V. Each amplifier can accept a ± 200 mV differential input. Both current sense amplifiers have a fixed gain of 12.5 and utilize an internal 2.5 V reference.

An analog comparator is also provided with each amplifier for fault detection. The threshold is defined as

$$1.2 \times \text{Full-Scale Voltage Range}$$

When this limit is reached, the output is latched onto a dedicated pin. This output remains high until the latch is cleared by writing to the appropriate register.

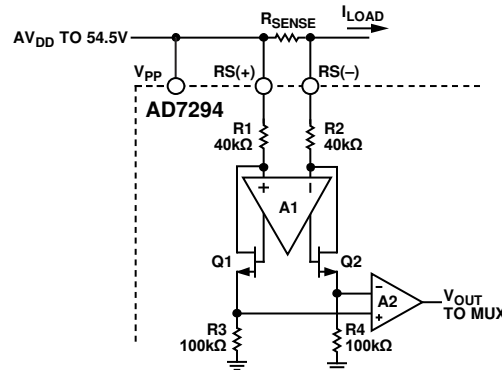


Figure 42. High-Side Current Sense

The AD7294 current sense comprises two main blocks: a differential and an instrumentation amplifier. A load current flowing through the external shunt resistor produces a voltage at the input terminals of the AD7294. Resistors R1 and R2 connect the input terminals to the differential amplifier (A1). A1 nulls the voltage appearing across its own input terminals by adjusting the current through R1 and R2 with Transistor Q1 and Transistor Q2. Common-mode feedback maintains the sum of these currents at approximately 50 μ A. When the input signal to the AD7294 is zero, the currents in R1 and R2 are equal. When the differential signal is nonzero, the current increases through one of the resistors and decreases in the other. The current difference is proportional to the size and polarity of the input signal.

The differential currents through Q1 and Q2 are converted into a differential voltage by R3 and R4. A2 is configured as an instrumentation amplifier, buffering this voltage and providing additional

gain. Therefore, for an input voltage of ± 200 mV at the pins, an output span of ± 2.5 V is generated.

The current sensors on the AD7294 are designed to remove any flicker noise and offset present in the sensed signal. This is achieved by implementing a chopping technique that is transparent to the user. The V_{SENSE} signal is first converted by the AD7294, the analog inputs to the amplifiers are then swapped, and the differential voltage is once again converted by the AD7294. The two conversion results enable the digital removal of any offset or noise. Switches on the amplifier inputs enable this chopping technique to be implemented. This process requires 6 μ s in total to return a final result.

Choosing R_{SENSE}

The resistor values used in conjunction with the current sense amplifiers on the AD7294 are determined by the specific application requirements in terms of voltage, current, and power. Small resistors minimize power dissipation, have low inductance to prevent any induced voltage spikes, and have good tolerance, which reduce current variations. The final values chosen are a compromise between low power dissipation and good accuracy. Low value resistors have less power dissipated in them, but higher value resistors may be required to utilize the full input range of the ADC, thus achieving maximum SNR performance.

When the sense current is known, the voltage range of the AD7294 current sensor (200 mV) is divided by the maximum sense current to yield a suitable shunt value. If the power dissipation in the shunt resistor is too large, the shunt resistor can be reduced, in which case, less of the ADC input range is used. Using less of the ADC input range results in conversion results, which are more susceptible to noise and offset errors because offset errors are fixed and are thus more significant when smaller input ranges are used.

R_{SENSE} must be able to dissipate the I^2R losses. If the power dissipation rating of the resistor is exceeded, its value may drift or the resistor may be damaged resulting in an open circuit. This can result in a differential voltage across the terminals of the AD7294 in excess of the absolute maximum ratings. Additional protection is afforded to the current sensors on the AD7294 by the recommended current limiting resistors, RF1 and RF2, as illustrated in Figure 43. The AD7294 can handle a maximum continuous current of 30 mA; thus, an RF2 of 1 k Ω provides adequate protection for the AD7294.

If I_{SENSE} has a large high frequency component, take care to choose a resistor with low inductance. Low inductance metal film resistors are best suited for these applications.

Current Sense Filtering

In some applications, it may be desirable to use external filtering to reduce the input bandwidth of the amplifier (see Figure 43). The -3 dB differential bandwidth of this filter is equal to

$$BW_{DM} = 1/(4\pi RC)$$

Note that the maximum series resistance on the RS(+) and RS(−) inputs (as shown in Figure 42) is limited to a maximum of 1 k Ω due to back-to-back ESD protection diodes from RS(+) and RS(−) to V_{PP} . Also, note that if RF1 and RF2 are in series with R1 and R2 (shown in Figure 42), it affects the gain of the amplifier. Any mismatch between RF1 and RF2 can introduce offset error.

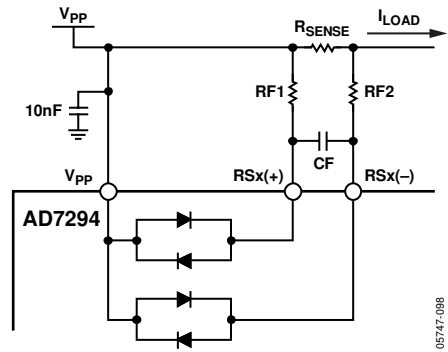


Figure 43. Current Sense Filtering (RS_x Can Be Either $RS1$ or $RS2$)

For certain RF applications, the optimum value for RF1 and RF2 is 1 k Ω whereas CF1 can range from 1 μ F to 10 μ F. CF2 is a decoupling capacitor for the V_{PP} supply. Its value is application dependent, but for initial evaluation, values in the range of 1 nF to 100 nF are recommended.

Kelvin Sense Resistor Connection

When using a low value sense resistor for high current measurement, the problem of parasitic series resistance can arise. The lead resistance can be a substantial fraction of the rated resistance, making the total resistance a function of lead length. Avoid this problem by using a Kelvin sense connection. This type of connection separates the current path through the resistor and the voltage drop across the resistor. Figure 44 shows the correct way to connect the sense resistor between the RS(+) and RS(−) pins of the AD7294.

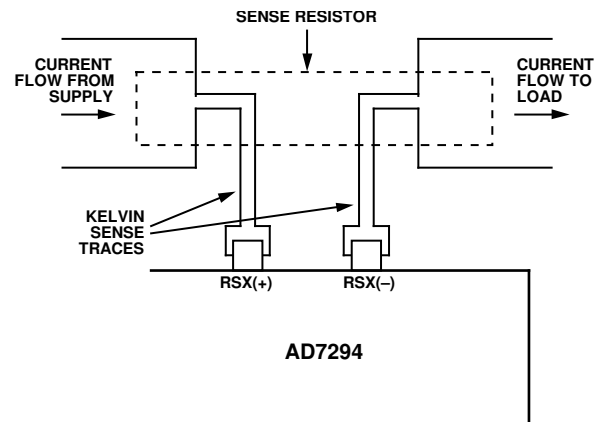


Figure 44. Kelvin Sense Connections (RS_x Can Be Either $RS1$ or $RS2$)

ANALOG COMPARATOR LOOP

The AD7294 contains two setpoint comparators that are used for independent analog control. This circuitry enables users to quickly detect if the sensed voltage across the shunt has

increased about the preset $(V_{REF} \times 1.2)/12.5$. If this occurs, the I_{SENSE} OVERRANGE pin is set to a high logic level enabling appropriate action to be taken to prevent any damage to the external circuitry.

The setpoint threshold level is fixed internally in the AD7294, and the current sense amplifier saturates above this level. The comparator also triggers if a voltage of less than AV_{DD} is applied to the R_{SENSE} or V_{PP} pin.

TEMPERATURE SENSOR

The AD7294 contains one local and two remote temperature sensors. The temperature sensors continuously monitor the three temperature inputs and new readings are automatically available every 5 ms.

The on-chip, band gap temperature sensor measures the temperature of the system. Diodes are used in conjunction with the two remote temperature sensors to monitor the temperature of other critical board components.

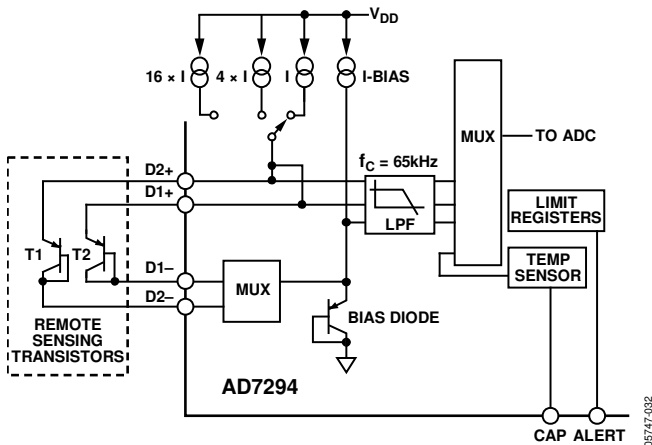


Figure 45. Internal and Remote Temperature Sensors

The temperature sensor module on the AD7294 is based on the three current principle (see Figure 45), where three currents are passed through a diode and the forward voltage drop is measured at each diode, allowing the temperature to be calculated free of errors caused by series resistance.

Each input integrates, in turn, over a period of several hundred microseconds. This takes place continuously in the background, leaving the user free to perform conversions on the other channels. When integration is complete, a signal passes to the control logic to initiate a conversion automatically. If the ADC is in command mode, the temperature conversion is performed as soon as the next conversion is completed. In autcycle mode, the conversion is inserted into an appropriate place in the current sequence; see the Register Setting section for further details. If the ADC is idle, the conversion takes place immediately.

Three registers store the result of the last conversion on each temperature channel; these can be read at any time. In addition, in command mode, one or both of the two external channel registers can be read out as part of the output sequence.

Remote Sensing Diode

The AD7294 is designed to work with discrete transistors, 2N3904 and 2N3906. If an alternative transistor is used, the AD7294 operates as specified provided the following conditions are adhered to.

Ideality Factor

The ideality factor, n_f , of the transistor is a measure of the deviation of the thermal diode from ideal behavior. The AD7294 is trimmed for an n_f value of 1.008. Use the following equation to calculate the error introduced at a Temperature T ($^{\circ}\text{C}$) when using a transistor whose n_f does not equal 1.008:

$$\Delta T = (n_f - 1.008) \times (273.15 \text{ K} + T)$$

To factor this in, the user can write the ΔT value to the offset register. The AD7294 automatically adds it to, or subtracts it from, the temperature measurement.

Base Emitter Voltage

The AD7294 operates as specified provided that the base-emitter voltage is greater than 0.25 V at 8 μA at the highest operating temperature, and less than 0.95 V at 128 μA for the lowest operating temperature.

Base Resistance

The base resistance should be less than 100 Ω .

h_{FE} Variation

Use a transistor with small variation in h_{FE} (approximately 50 to 150). Small variation in h_{FE} indicates tight control of the V_{BE} characteristics.

For RF applications, the use of high Q capacitors functioning as a filter protects the integrity of the measurement. These capacitors, such as Johanson Technology 10 pF high Q capacitors: Reference Code 500R07S100JV4T, should be connected between the base and the emitter, as close to the external device as possible. However, large capacitances affect the accuracy of the temperature measurement; thus, the recommended maximum capacitor value is 100 pF. In most cases, a capacitor is not required; the selection of any capacitor is dependent on the noise frequency level.

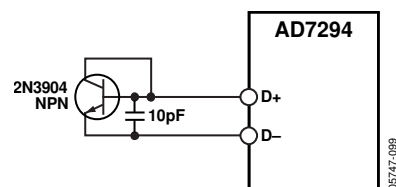


Figure 46. Measuring Temperature Using an NPN Transistor

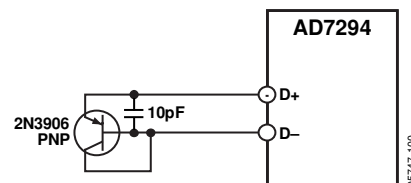


Figure 47. Measuring Temperature Using a PNP Transistor